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November 2013

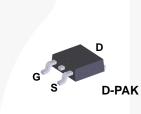
## FQD4P25TM\_WS P-Channel QFET<sup>®</sup> MOSFET -250 V, -3.1 A, 2.1 Ω

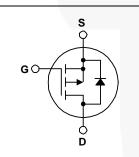
### Description

This P-Channel enhancement mode power MOSFET is produced using Fairchild Semiconductor's proprietary planar stripe and DMOS technology. This advanced MOSFET technology has been especially tailored to reduce on-state resistance, and to provide superior switching performance and high avalanche energy strength. These devices are suitable for switched mode power supplies, audio amplifier, DC motor control, and variable switching power applications.

#### Features

- -3.1 A, -250 V,  $R_{DS(on)}$  = 2.1  $\Omega$  (Max.) @ V<sub>GS</sub> = 10 V, I<sub>D</sub> = -1.55 A
- Low Gate Charge (Typ. 10 nC)
- Low Crss (Typ. 10.3 pF)
- 100% Avalanche Tested
- Improved dv/dt Capability
- RoHS Compliant





#### Absolute Maximum Ratings T<sub>c</sub> = 25°C unless otherwise noted.

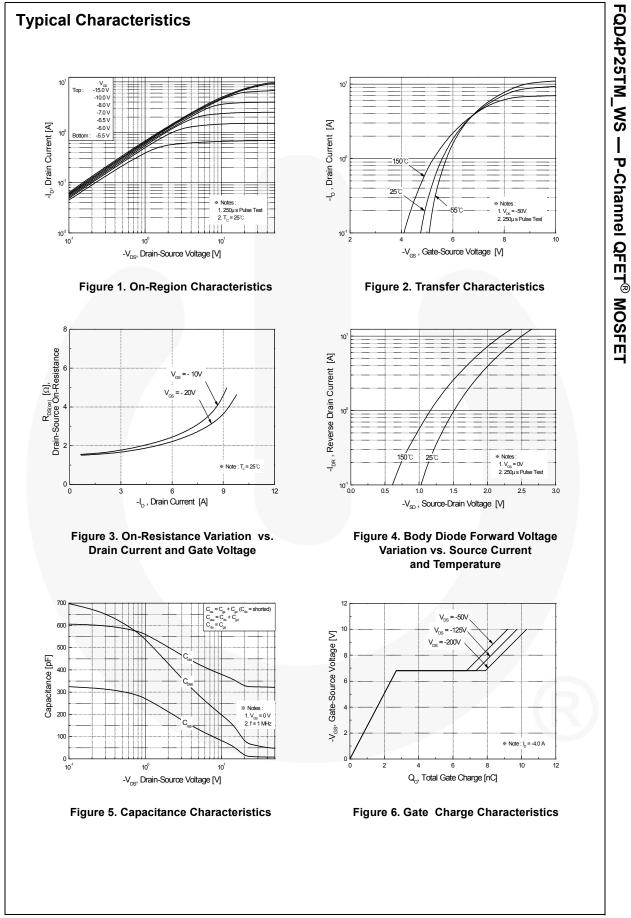
Symbol	Parameter	FQD4P25TM_WS	Unit		
V <sub>DSS</sub>	Drain-Source Voltage		-250	V	
I <sub>D</sub>	Drain Current - Continuous ( $T_C = 25^{\circ}C$ )		-3.1	А	
	- Continuous (T <sub>C</sub> = 100°C)		-1.96	А	
I <sub>DM</sub>	Drain Current - Pulsed	(Note 1)	-12.4	А	
V <sub>GSS</sub>	Gate-Source Voltage		± 30	V	
E <sub>AS</sub>	Single Pulsed Avalanche Energy (Note 2)		280	mJ	
I <sub>AR</sub>	Avalanche Current (Note 1)		-3.1	А	
E <sub>AR</sub>	Repetitive Avalanche Energy (Note 1)		4.5	mJ	
dv/dt	Peak Diode Recovery dv/dt (Note 3)		-5.5	V/ns	
P <sub>D</sub>	Power Dissipation ( $T_A = 25^{\circ}C$ ) *	2.5	W		
	Power Dissipation ( $T_C = 25^{\circ}C$ )	45	W		
	- Derate above 25°C	0.36	W/°C		
T <sub>J</sub> , T <sub>STG</sub>	Operating and Storage Temperature Range		-55 to +150	°C	
т <sub>L</sub>	Maximum lead temperature for soldering,		300	°C	
L	1/8" from case for 5 seconds			Ŭ	

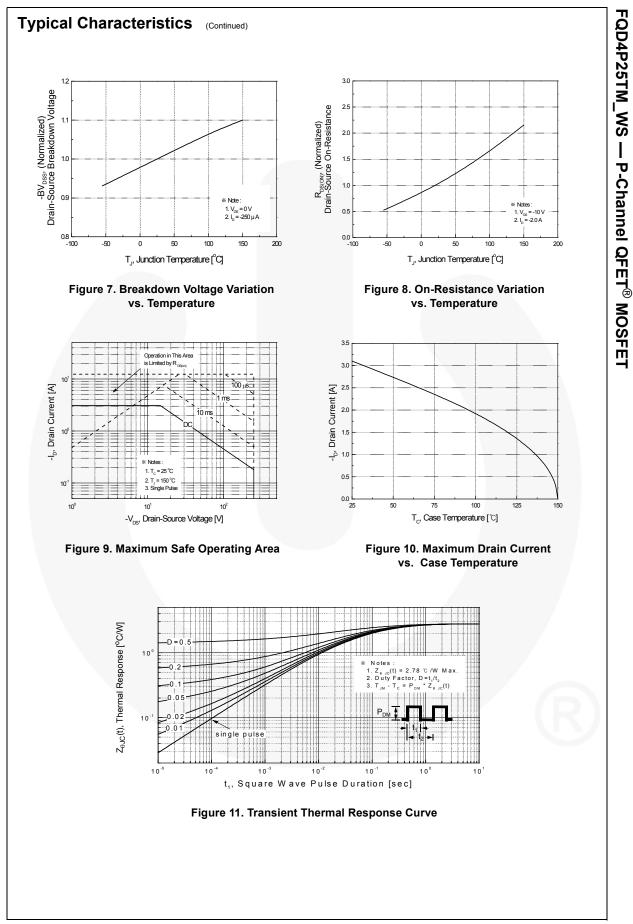
### **Thermal Characteristics**

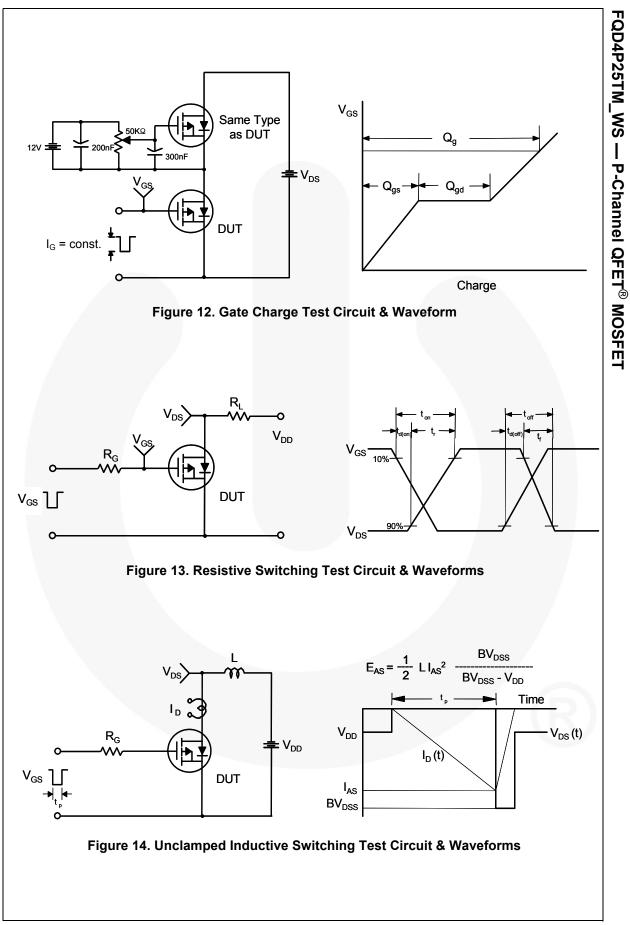
Symbol	Parameter	FQD4P25TM_WS	Unit	
$R_{\thetaJC}$	Thermal Resistance, Junction to Case, Max.	2.78		
D	Thermal Resistance, Junction to Ambient (Minimum Pad of 2-oz Copper), Max.	110	°C/W	
$R_{\theta J A}$	Thermal Resistance, Junction to Ambient (*1 in <sup>2</sup> Pad of 2-oz Copper), Max.	50		

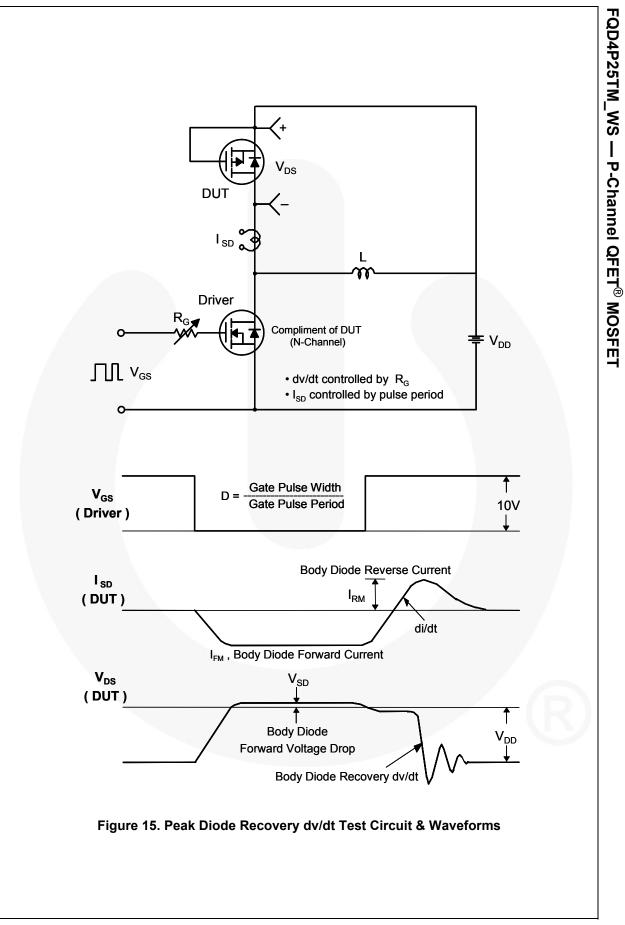
Part Number FQD4P25TM_WS		Top Mark	Pac	ackage Packing Method Ree		d Ree	Size	Tape Width		Quantity	
		FQD4P25S		DPAK Tape and Reel 330			mm	16 mm		2500 units	
lectri	cal Char	acteristics	T <sub>C</sub> = 25°C	cunless oth	erwise noted.						
Symbol		Parameter			Test Conditions		Min.	Тур.	Max.	Unit	
Off Cha	racteristic	` <b>c</b>									
BV <sub>DSS</sub>	Drain-Source Breakdown Voltage		е	V <sub>GS</sub> = 0 V, I <sub>D</sub> = -250 μA			-250			V	
ΔBV <sub>DSS</sub> / ΔTJ	Breakdown Voltage Temperature   ATJ   Coefficient   Zero Gate Voltage Drain Current		$I_D = -250 \ \mu$ A, Referenced to 25°C				-0.21		V/°C		
DSS			$V_{DS} = -250 V, V_{GS} = 0 V$ $V_{DS} = -200 V, T_{C} = 125^{\circ}C$					-1 -10	μA μA		
GSSF			rward	$V_{GS} = -30 \text{ V}, V_{DS} = 0 \text{ V}$					-100	nA	
GSSR	-	Leakage Current, Re			30 V, V <sub>DS</sub> = 0 V				100	nA	
	,	<u> </u>									
Jn Cna / <sub>GS(th)</sub>	Gate Thresh	s Nold Voltage			/ <sub>GS</sub> , I <sub>D</sub> = -250 μA		-3.0		-5.0	V	
RDS(on)	Static Drain On-Resistar	-Source			·10 V, I <sub>D</sub> = -1.55 A			1.63	2.1	Ω	
JFS		ansconductance		V <sub>DS</sub> = -40 V, I <sub>D</sub> = -1.55 A				2.0		S	
	ic Charact			00					<u> </u>		
C <sub>iss</sub>	Input Capac			V	$25 V V_{re} = 0 V$			325	420	pF	
C <sub>oss</sub>	Output Cap		-	V <sub>DS</sub> = -25 V, V <sub>GS</sub> = 0 V, f = 1.0 MHz				65	85	pF	
Crss		ansfer Capacitance						10	13	pF	
Switchi	ng Charac	cteristics									
d(on)	Turn-On De	lay Time		Vpp = -	-125 V, I <sub>D</sub> = -4.0 A			9.5	30	ns	
r	Turn-On Ris	se Time		R <sub>G</sub> = 2		,		60	130	ns	
d(off)	Turn-Off De	lay Time		U U				14	40	ns	
f	Turn-Off Fa	ll Time				(Note 4)		27	65	ns	
ე <sub>მ</sub>	Total Gate C	Charge		$V_{DS}$ = -200 V, I <sub>D</sub> = -4.0 A, V <sub>GS</sub> = -10 V		,		10.3	14	nC	
ୁ <sub>gs</sub>	Gate-Sourc	e Charge						2.7		nC	
ე <sub>gd</sub>	Gate-Drain	Charge				(Note 4)		5.2		nC	
Drain-S	ource Dio	de Characterist	ics an	nd Max	imum Ratings	5					
S	Maximum C	ontinuous Drain-Sou	rce Dio	de Forwa	ard Current				-3.1	Α	
SM	Maximum P	ulsed Drain-Source I	Diode F						-12.4	А	
/ <sub>SD</sub>	Drain-Source	e Diode Forward Vol	tage		) V, I <sub>S</sub> = -3.1 A				-5.0	V	
rr	Reverse Re	covery Time			0 V, I <sub>S</sub> = -4.0 A,			140		ns	
ວ <sub>rr</sub>	Reverse Re	covery Charge		dI <sub>F</sub> / dt	= 100 A/µs			0.64		μC	
L = 46.6  mH $I_{SD} \le -4.0 \text{ /}$	H, I <sub>AS</sub> = -3.1 A, V <sub>D</sub> A, diVdt≤ 300 AVµ	limited by maximum Huncti $_{D}$ = -50V, R <sub>G</sub> = 25 $\Omega$ , startir is, V <sub>DD</sub> $\leq$ BV <sub>DSS</sub> , starting T erating temperature.									

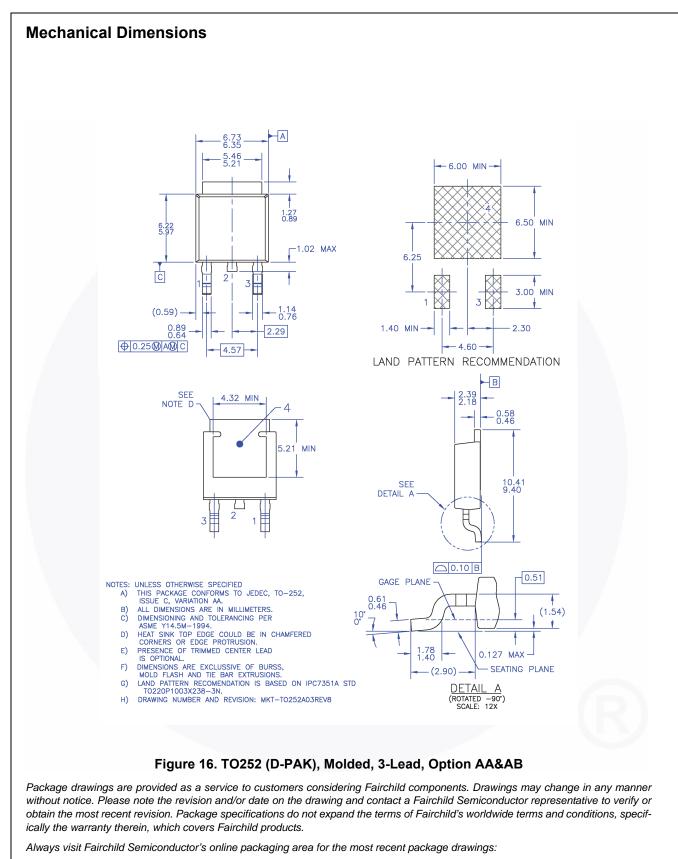
FQD4P25TM\_WS — P-Channel QFET<sup>®</sup> MOSFET











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